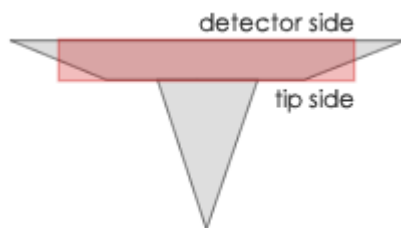


Cantilever Data	Value	Range*
<b>Resonance Frequency</b>	<b>75 kHz</b>	60 - 90 kHz
<b>Force Constant</b>	<b>2.8 N/m</b>	1.2 - 5.5 N/m
<b>Length</b>	<b>225 <math>\mu\text{m}</math></b>	220 - 230 $\mu\text{m}$
<b>Mean Width</b>	<b>28 <math>\mu\text{m}</math></b>	22.5 - 32.5 $\mu\text{m}$
<b>Thickness</b>	<b>3 <math>\mu\text{m}</math></b>	2.5 - 3.5 $\mu\text{m}$

NanoWorld® Pointprobe® FM probes are designed for force modulation mode imaging.. The force constant of the FM type fills the gap between contact and non-contact probes. Furthermore non-contact or tapping mode imaging is possible with this AFM probe.

All SPM and AFM probes of the Pointprobe® series are made from monolithic silicon which is highly doped to dissipate static charge. They are chemically inert and offer a high mechanical Q-factor for high sensitivity. The AFM tip is shaped like a polygon based pyramid with a typical height of 10 - 15  $\mu\text{m}$ .

Additionally, this AFM probe offers typical AFM tip radius of curvature of less than 8 nm.



A trapezoidal cross section of the AFM cantilever and therefore 30% wider (e.g. NCH) AFM cantilever detector side result in easier and faster laser adjustment. Additionally, because there is simply more space to place and reflect the laser beam, a higher SUM signal is reached.

Tip shape: Standard  
Coating: none

Order Code	Quantity	Data Sheet
FM-10	10	yes
FM-20	20	yes
FM-50	50	no
FM-W	380	yes



NanoWorld® Pointprobe® Silicon AFM Probes Screencast (Standard AFM Tip)

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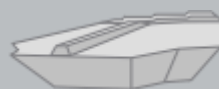
For detailed information about our AFM probe product series please see below:



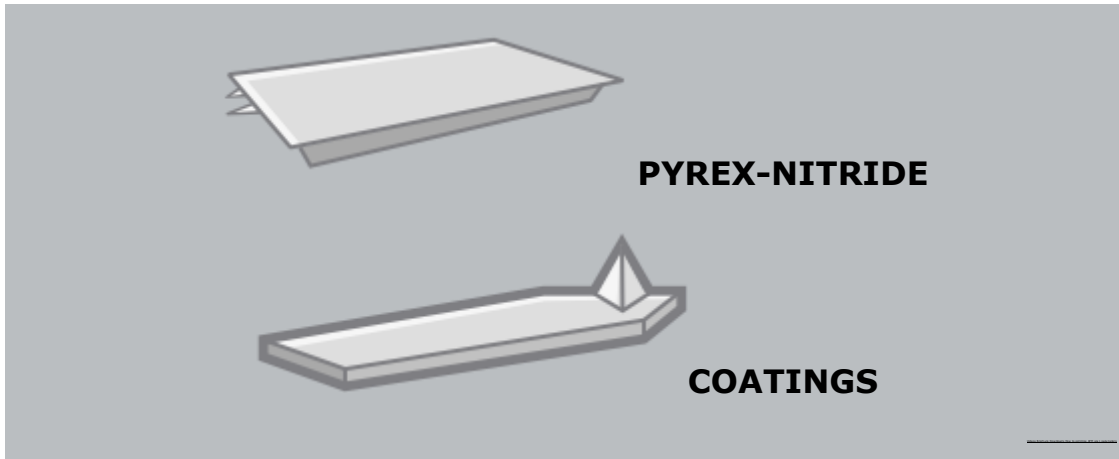
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